

## IEEE Std. 1149.1 (JTAG) Boundary Scan Support

All Cyclone® devices provide JTAG BST circuitry that complies with the IEEE Std. 1149.1a-1990 specification. JTAG boundary-scan testing can be performed either before or after, but not during configuration. Cyclone devices can also use the JTAG port for configuration together with either the Quartus® II software or hardware using either Jam Files (.jam) or Jam Byte-Code Files (.jbc).

Cyclone devices support reconfiguring the I/O standard settings on the IOE through the JTAG BST chain. The JTAG chain can update the I/O standard for all input and output pins any time before or during user mode. Designers can use this ability for JTAG testing before configuration when some of the Cyclone pins drive or receive from other devices on the board using voltage-referenced standards. Since the Cyclone device might not be configured before JTAG testing, the I/O pins might not be configured for appropriate electrical standards for chip-to-chip communication. Programming those I/O standards via JTAG allows designers to fully test I/O connection to other devices.

The JTAG pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The TDO pin voltage is determined by the  $V_{CCIO}$  of the bank where it resides. The bank  $V_{CCIO}$  selects whether the JTAG inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

Cyclone devices also use the JTAG port to monitor the operation of the device with the SignalTap® II embedded logic analyzer. Cyclone devices support the JTAG instructions shown in [Table 3-1](#).

**Table 3-1. Cyclone JTAG Instructions (Part 1 of 2)**

| JTAG Instruction | Instruction Code | Description   |
|------------------|------------------|---|
| SAMPLE/PRELOAD   | 00 0000 0101     | Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap II embedded logic analyzer. |
| EXTEST (1)       | 00 0000 0000     | Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.   |
| BYPASS           | 11 1111 1111     | Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.   |

**Table 3–1. Cyclone JTAG Instructions (Part 2 of 2)**

| JTAG Instruction          | Instruction Code | Description  |
|---------------------------|------------------|--|
| USERCODE                  | 00 0000 0111     | Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.  |
| IDCODE                    | 00 0000 0110     | Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.  |
| HIGHZ (1)                 | 00 0000 1011     | Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.   |
| CLAMP (1)                 | 00 0000 1010     | Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.  |
| ICR instructions          | —                | Used when configuring a Cyclone device via the JTAG port with a MasterBlaster™ or ByteBlasterMV™ download cable, or when using a Jam File or Jam Byte-Code File via an embedded processor.   |
| PULSE_NCONFIG             | 00 0000 0001     | Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.  |
| CONFIG_IO                 | 00 0000 1101     | Allows configuration of I/O standards through the JTAG chain for JTAG testing. Can be executed before, after, or during configuration. Stops configuration if executed during configuration. Once issued, the CONFIG_IO instruction will hold nSTATUS low to reset the configuration device. nSTATUS is held low until the device is reconfigured. |
| SignalTap II instructions | —                | Monitors internal device operation with the SignalTap II embedded logic analyzer.  |

**Note to Table 3–1:**

- (1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

In the Quartus II software, there is an Auto Usercode feature where you can choose to use the checksum value of a programming file as the JTAG user code. If selected, the checksum is automatically loaded to the USERCODE register. Choose Assignments > Device > Device and Pin Options > General. Turn on **Auto Usercode**.

The Cyclone device instruction register length is 10 bits and the USERCODE register length is 32 bits. Tables 3–2 and 3–3 show the boundary-scan register length and device IDCODE information for Cyclone devices.

| Device | Boundary-Scan Register Length |
|--------|-------------------------------|
| EP1C3  | 339                           |
| EP1C4  | 930                           |
| EP1C6  | 582                           |
| EP1C12 | 774                           |
| EP1C20 | 930                           |

| Device | IDCODE (32 bits) (1) |                       |                                 |                 |
|--------|----------------------|-----------------------|---------------------------------|-----------------|
|        | Version (4 Bits)     | Part Number (16 Bits) | Manufacturer Identity (11 Bits) | LSB (1 Bit) (2) |
| EP1C3  | 0000                 | 0010 0000 1000 0001   | 000 0110 1110                   | 1               |
| EP1C4  | 0000                 | 0010 0000 1000 0101   | 000 0110 1110                   | 1               |
| EP1C6  | 0000                 | 0010 0000 1000 0010   | 000 0110 1110                   | 1               |
| EP1C12 | 0000                 | 0010 0000 1000 0011   | 000 0110 1110                   | 1               |
| EP1C20 | 0000                 | 0010 0000 1000 0100   | 000 0110 1110                   | 1               |

**Notes to Table 3–3:**

- (1) The most significant bit (MSB) is on the left.
- (2) The IDCODE's least significant bit (LSB) is always 1.

Figure 3-1 shows the timing requirements for the JTAG signals.

**Figure 3-1. Cyclone JTAG Waveforms**

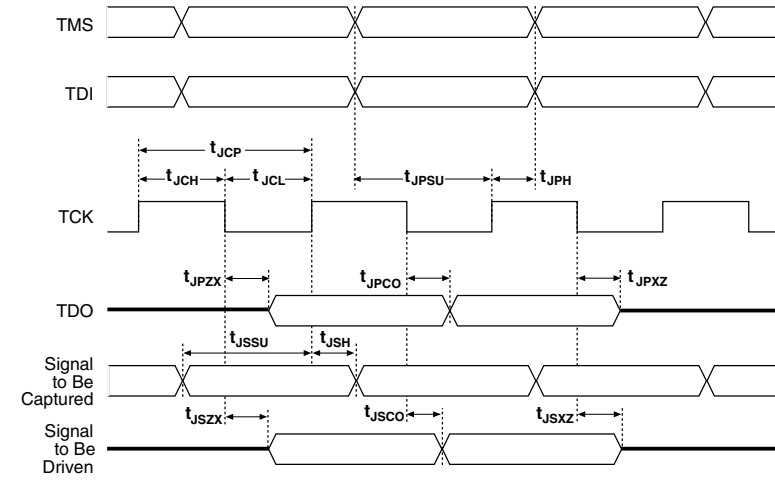


Table 3-4 shows the JTAG timing parameters and values for Cyclone devices.

| Symbol     | Parameter                                      | Min | Max | Unit |
|------------|--|-----|-----|------|
| $t_{JCP}$  | TCK clock period                               | 100 | —   | ns   |
| $t_{JCH}$  | TCK clock high time                            | 50  | —   | ns   |
| $t_{JCL}$  | TCK clock low time                             | 50  | —   | ns   |
| $t_{JPSU}$ | JTAG port setup time                           | 20  | —   | ns   |
| $t_{JPH}$  | JTAG port hold time                            | 45  | —   | ns   |
| $t_{JPCO}$ | JTAG port clock to output                      | —   | 25  | ns   |
| $t_{JPZX}$ | JTAG port high impedance to valid output       | —   | 25  | ns   |
| $t_{JPXZ}$ | JTAG port valid output to high impedance       | —   | 25  | ns   |
| $t_{JSSU}$ | Capture register setup time                    | 20  | —   | ns   |
| $t_{JSH}$  | Capture register hold time                     | 45  | —   | ns   |
| $t_{JSCO}$ | Update register clock to output                | —   | 35  | ns   |
| $t_{JSZX}$ | Update register high impedance to valid output | —   | 35  | ns   |
| $t_{JSXZ}$ | Update register valid output to high impedance | —   | 35  | ns   |



Cyclone devices must be within the first 8 devices in a JTAG chain. All of these devices have the same JTAG controller. If any of the Cyclone devices are in the 9th or after they will fail configuration. This does not affect the SignalTap® II logic analyzer.



For more information on JTAG, refer to the following documents:

- *AN 39: IEEE Std. 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices*
- *Jam Programming & Test Language Specification*

## SignalTap II Embedded Logic Analyzer

Cyclone devices feature the SignalTap II embedded logic analyzer, which monitors design operation over a period of time through the IEEE Std. 1149.1 (JTAG) circuitry. A designer can analyze internal logic at speed without bringing internal signals to the I/O pins. This feature is particularly important for advanced packages, such as FineLine BGA packages, because it can be difficult to add a connection to a pin during the debugging process after a board is designed and manufactured.

## Configuration

The logic, circuitry, and interconnects in the Cyclone architecture are configured with CMOS SRAM elements. Altera FPGAs are reconfigurable and every device is tested with a high coverage production test program so the designer does not have to perform fault testing and can instead focus on simulation and design verification.

Cyclone devices are configured at system power-up with data stored in an Altera configuration device or provided by a system controller. The Cyclone device's optimized interface allows the device to act as controller in an active serial configuration scheme with the new low-cost serial configuration device. Cyclone devices can be configured in under 120 ms using serial data at 20 MHz. The serial configuration device can be programmed via the ByteBlaster II download cable, the Altera Programming Unit (APU), or third-party programmers.

In addition to the new low-cost serial configuration device, Altera offers in-system programmability (ISP)-capable configuration devices that can configure Cyclone devices via a serial data stream. The interface also enables microprocessors to treat Cyclone devices as memory and configure them by writing to a virtual memory location, making reconfiguration easy. After a Cyclone device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Real-time changes can be made during system operation, enabling innovative reconfigurable computing applications.

## Operating Modes

The Cyclone architecture uses SRAM configuration elements that require configuration data to be loaded each time the circuit powers up. The process of physically loading the SRAM data into the device is called configuration. During initialization, which occurs immediately after configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. Together, the configuration and initialization processes are called command mode. Normal device operation is called user mode.

SRAM configuration elements allow Cyclone devices to be reconfigured in-circuit by loading new configuration data into the device. With real-time reconfiguration, the device is forced into command mode with a device pin. The configuration process loads different configuration data, reinitializes the device, and resumes user-mode operation. Designers can perform in-field upgrades by distributing new configuration files either within the system or remotely.

A built-in weak pull-up resistor pulls all user I/O pins to  $V_{CCIO}$  before and during device configuration.

The configuration pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The voltage level of the configuration output pins is determined by the  $V_{CCIO}$  of the bank where the pins reside. The bank  $V_{CCIO}$  selects whether the configuration inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

## Configuration Schemes

Designers can load the configuration data for a Cyclone device with one of three configuration schemes (see [Table 3–5](#)), chosen on the basis of the target application. Designers can use a configuration device, intelligent controller, or the JTAG port to configure a Cyclone device. A low-cost configuration device can automatically configure a Cyclone device at system power-up.

Multiple Cyclone devices can be configured in any of the three configuration schemes by connecting the configuration enable ( $nCE$ ) and configuration enable output ( $nCEO$ ) pins on each device.

**Table 3–5. Data Sources for Configuration**

| Configuration Scheme | Data Source   |
|----------------------|---|
| Active serial        | Low-cost serial configuration device  |
| Passive serial (PS)  | Enhanced or EPC2 configuration device, MasterBlaster or ByteBlasterMV download cable, or serial data source |
| JTAG                 | MasterBlaster or ByteBlasterMV download cable or a microprocessor with a Jam or JBC file                    |

## Referenced Documents

This chapter references the following document:

- [AN 39: IEEE Std. 1149.1 \(JTAG\) Boundary-Scan Testing in Altera Devices](#)
- [Jam Programming & Test Language Specification](#)

## Document Revision History

Table 3–6 shows the revision history for this chapter.

**Table 3–6. Document Revision History**

| Date and Document Version | Changes Made   | Summary of Changes |
|---------------------------|--|--------------------|
| May 2008 v1.4             | Minor textual and style changes. Added “Referenced Documents” section.   | —                  |
| January 2007 v1.3         | <ul style="list-style-type: none"> <li>● Added document revision history.</li> <li>● Updated handpara note below Table 3–4.</li> </ul> | —                  |
| August 2005 V1.2          | Minor updates.   | —                  |
| February 2005 V1.1        | Updated JTAG chain limits. Added information concerning test vectors.  | —                  |
| May 2003 v1.0             | Added document to Cyclone Device Handbook.   | —                  |

